

Search Notes



Application/Control No.

10/681,647

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

KIM ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	540	07.22.04	Mo
	541	↓	↓
	538		
	539		
	542		
	543	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST See attachment	06.17.05	Mo